Towards a method for quantitative evaluation of nanoparticles in suspension via Microprinting and **SEM analysis**



Bundesanstalt für Materialforschung und -prüfung

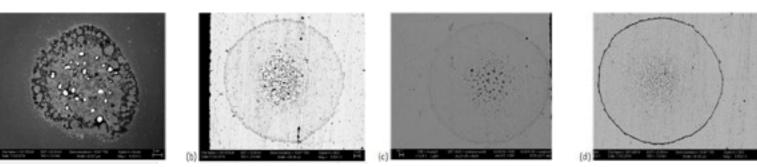
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Background: Physico-chemical propeties of NMs

- Nanomaterials (NMs) come into increasing use, requiring understanding of which **structural aspects** (size, shape, aspect ratio, surface chemistry) influence their **physico-chemical and** toxicological properties
- Development of a library of analytical methods is necessary, which can provide reliable, reproducible, accurate and validated data
- Method implementation is enabled by an increase in **efficiency** as well as trend towards miniaturisation and automation

Results

Droplet behaviour is very material-dependent

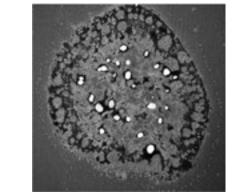


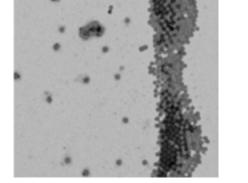
TSEM/SEM images of NPs printed at 40 $^{\circ}$ C and 30 $^{\circ}$ R.H. (a) Au100 (b) Au20 (c) PS (d) SiO₂

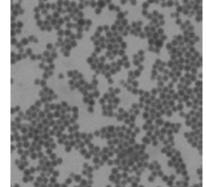
Lower temperature and higher relative humidity decreases coffee-ring effect

Goal: NP PSD and Concentration

- Nanoparticles (NPs) in suspension need accurate methods for determination of their concentration / size distribution^[1-4]
- Printing droplets of the suspension and imaging with scanning electron microscopy (SEM) enables simultaneous evaluation of particle size distribution and concentration
- Image evaluation with software (Fiji/ImageJ)
- Requirements:
 - homogeneously dispersed
 - **isolated** (not aggregated) particles
 - in a **monolayer**,
 - sufficient concentrations for **statistically significant** evaluation
- Elimination of coffee ring effect





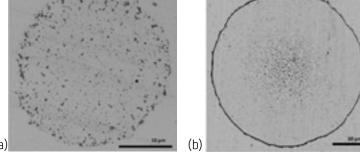


EAgglomerates & aggregates

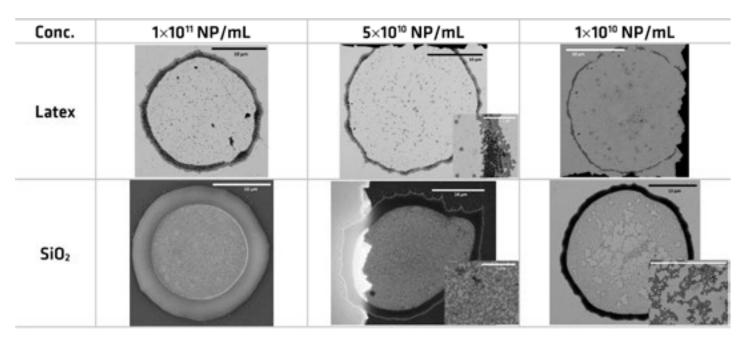
⊠ Agglomerate, coffee-ring effect

☑ Concentrated, no overlap

TSEM images of 1 x 10⁹ NP/ mL SiO₂ NPs printed at: (a) 21 °C / 80 % R.H. (b) 40 °C / 30 % R.H.

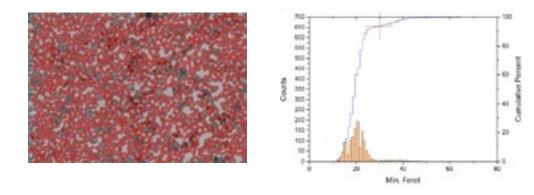


- Latex and SiO₂ NPs show improved coverage at higher concentrations and less coffee-ring effect at lower concentrations.
- Latex NPs have a much higher affinity for the substrate than each other. They form overlapping layers rather than single layers. Their low contrast makes digital image evaluation difficult.
- SiO₂ NPs shows a very strong coffee-ring effect, but also readily forms monolayers. These two effects compete.



SEM / TSEM images PS (Latex) and SiO₂ NPs printed at 21 °C and 80 % R.H. at varying concentrations

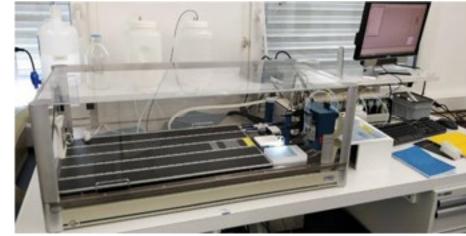
Maximum estimated concentration to form a monolayer calculated for 20 nm SiO₂ NPs (3 x 10^{12} NP/mL): higher than concentration at which coffee rings were found

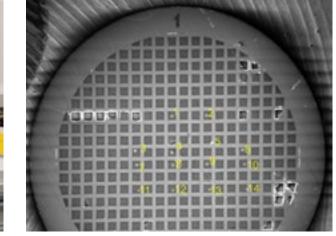


Estimate of particle concentration in monolayer using ImageJ software; the software is unable to distinguish between single particles and groups

Method

- Cu TEM grids coated with carbon film are printed with NP suspensions using a NanoPlotter (GeSim GmbH) piezo-electric printer
- Printing parameters (droplet volume, droplet speed, drop casting rate, printout drying) are optimised for each NP solution
- Different materials and sizes tested: Gold (Au) NPs (20 nm and 100 nm); Polystyrene NPs (100 nm) and SiO_2 (20 nm)
- Drops printed with a volume of 400 pL in a 4 x 4 array, with each suspension printed in 4 spots and grids repeated in triplicate





- Experimental parameters varied:
 - **Temperature** (21-40 °C)
 - **Relative humidity (R.H.)** (50-80 %)
 - NP concentration (10⁹-10¹¹ NP/mL)
- Imaged via SEM/TSEM

Summary & further work

- Options for reducing coffee-ring effect strongly limited by conditions available for printing
- Process must be optimised for each material type
- Further work with optimised substrates
- Au impurities/agglomeration may be due to ageing and salts from synthesis – these are not suitable for further work

Both types of Au NPs show large amounts of agglomerates/ aggregates and impurities, and are therefore not suitable for this method.

[1] K. Kumagai and A. Kurokawa, Metrologia 56 (2019) (4), p044001 [2] B. Michen, C. Geers, D. Vanhecke, C. Endes, B. Rothen-Rutishauser, S. Balog and A. Petri-Fink, Scientific Reports 5 (2015) (1), p9793. [3] J. Mielke, P. Dohányosová, P. Müller, S. López-Vidal and V.-D. Hodoroaba, Microscopy and Microanalysis 23 (2017) (1), pp°163-172. [4] R. Tannenberg, H. Eickhoff and W. Weigel, G.I.T. Imaging & Microscopy (2016), pp 33–35. The authors thank Sigrid Benemann for SEM measurements and Dr. Christoph Hörenz for assistance with image processing

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Sicherheit in Technik und Chemie





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